Unit: mm



TOSHIBA Field Effect Transistor Silicon P, N Channel MOS Type (U-MOS IV / U-MOS III)

# **TPCP8402**

Portable Equipment Applications
Mortor Drive Applications
DC-DC Converter Applications

- Low drain-source ON resistance
  - : P Channel RDS (ON) = 60 m $\Omega$  (typ.)
  - N Channel RDS (ON) =  $38 \text{ m}\Omega$  (typ.)
- High forward transfer admittance
  - : P Channel  $|Y_{fs}| = 6.0 \text{ S (typ.)}$
  - N Channel  $|Y_{fs}| = 7.0 \text{ S (typ.)}$
- Low leakage current
  - : P Channel IDSS =  $-10 \mu A (VDS = -30 V)$
  - N Channel IDSS =  $10 \mu A \text{ (VDS} = 30 \text{ V)}$
- Enhancement-mode
  - : P Channel  $V_{th} = -0.8$  to -2.0 V ( $V_{DS} = -10$  V,  $I_{D} = -1$ mA)
  - N Channel  $V_{th}$  = 1.3 to 2.5 V ( $V_{DS}$  = 10 V,  $I_{D}$  = 1mA)

#### **Maximum Ratings (Ta = 25°C)**

Cł	Symbol	Rating		Unit		
Drain-source v	Drain-source voltage			30	V	
Drain-gate vol	tage (R <sub>GS</sub> = 20 kΩ)	$V_{DGR}$	-30	30	V	
Gate-source v	oltage	V <sub>GSS</sub>	±20	±20	V	
Drain current	DC (Note 1)	ΙD	-3.4	4.2	Α	
Dialii cuiteili	Pulse (Note 1)	I <sub>DP</sub>	-13.6	16.8	^	
Drain power dissipation	Single-device operation (Note 3a)	P <sub>D (1)</sub>	1.48	1.48		
(t = 5 s) (Note 2a)	Single-device value at dual operation(Note 3b)	P <sub>D (2)</sub>	1.23	1.23	W	
Drain power dissipation (t = 5 s) (Note 2b)	Single-device operation (Note 3a)	P <sub>D (1)</sub>	0.58	0.58	VV	
	Single-device value at dual operation(Note 3b)	P <sub>D (2)</sub>	0.36	0.36		
Single pulse a	valanche energy(Note 4)	E <sub>AS</sub>	0.75	2.86	mJ	
Avalanche cur	I <sub>AR</sub>	-1.7	2.1	Α		
Repetitive ava Single-device	E <sub>AR</sub>	0.12		mJ		
Channel tempo	T <sub>ch</sub>	150		°C		
Storage temper	T <sub>stg</sub>	-55~150		°C		

Note: For (Note 1), (Note 2), (Note 3), (Note 4), (Note 5) and (Note 6), please refer to the next page.

This transistor is an electrostatic sensitive device. Please handle with caution.

( Note 7 )

1 . Source 1 5 . Drain 2

2 . Gate1 6 . Drain2 3 . Source2 7 . Drain1

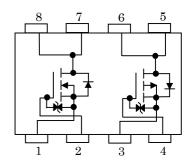
3 . Source 2 7 . Drain 1 4 . Gate 2 8 . Drain 1

JEDEC —

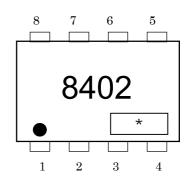
JEITA —
TOSHIBA —

Weight: 0.017 g (typ.)

### **Circuit Configuration**



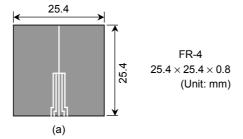
#### Marking (Note 6)

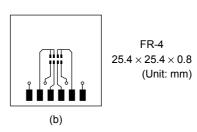


#### **Thermal Characteristics**

Charac	Symbol	Max	Unit		
Thermal resistance, channel to ambient (t = 5 s) (Note 2a)	Single-device operation (Note 3a) Rth (ch-a) (		84.5	°C/W	
	Single-device value at dual operation (Note 3b)	R <sub>th (ch-a) (2)</sub>	101.6	C/VV	
Thermal resistance, channel to ambient	Single-device operation (Note 3a)	R <sub>th (ch-a) (1)</sub>	215.5	°C/W	
(t = 5 s) (Note 2b)	Single-device value at dual operation (Note 3b)	R <sub>th (ch-a) (2)</sub>	347.2	C/VV	

- Note 1: Please use devices on condition that the channel temperature is below 150°C.
- Note 2: (a) Device mounted on a glass-epoxy board (b) Device mounted on a glass-epoxy board (b)





- Note 3: a) The power dissipation and thermal resistance values are shown for a single device (During single-device operation, power is only applied to one device.).
  - b) The power dissipation and thermal resistance values are shown for a single device (During dual operation, power is evenly applied to both devices.).
- Note 4: P Channel:  $V_{DD}=-24$  V,  $T_{ch}=25^{\circ}C$  (initial), L=0.2 mH,  $R_G=25$   $\Omega$ ,  $I_{AR}=-1.7$  A N Channel:  $V_{DD}=24$  V,  $T_{ch}=25^{\circ}C$  (initial), L=0.5 mH,  $R_G=25$   $\Omega$ ,  $I_{AR}=2.1$  A
- Note 5: Repetitive rating; Pulse width limited by maximum channel temperature.
- Note 6: Black round marking " " locates on the left lower side of parts number marking "8402" indicates terminal No. 1.
  - No. 1.

    "\*" shows lot number, which is a three digit number. The first digit number expresses the year of manufacture: last decimel digit of the year of manufacture, the next two digit number expresses the week of manufacture.

P-ch

# **Electrical Characteristics (Ta = 25°C)**

Cha	aracteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I <sub>GSS</sub>	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μΑ
Drain cut-off curre	ent	I <sub>DSS</sub>	$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}$	_	_	10	μΑ
Drain-source brea	akdown voltage	V <sub>(BR)DSS</sub>	$I_D = -10 \text{ mA}, V_{GS} = 0 \text{ V}$	-30	_	_	V
Drain-source breakdown voltage		V <sub>(BR)DSX</sub>	$I_D = -10 \text{ mA}, V_{GS} = 20 \text{ V}$	-15	_	_	V
Gate threshold vo	oltage	V <sub>th</sub>	$V_{DS} = -10 \text{ V}, I_D = -1 \text{ mA}$	-0.8	_	-2.0	V
Drain-source ON resistance		R <sub>DS (ON)</sub>	$V_{GS} = -4.5 \text{ V}, I_D = -1.7 \text{ A}$		80	105	mΩ
Brain-30dice ON	resistance	NDS (ON)	$V_{GS} = -10 \text{ V}, I_D = -1.7 \text{ A}$		60	72	11122
Forward transfer	admittance	Y <sub>fs</sub>	$V_{DS} = -10 \text{ V}, I_D = -1.7 \text{ A}$	3.0	6.0	_	S
Input capacitance		C <sub>iss</sub>	V <sub>DS</sub> = -10 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	600	_	pF
Reverse transfer capacitance		C <sub>rss</sub>		_	60	_	
Output capacitance		Coss		_	70	_	
Switching time	Rise time	t <sub>r</sub>	$V_{GS}$ $0 \text{ V}$ $I_D = -1.7 \text{ A}$ $0 \text{ V}$ $0 \text{ V}$ $0 \text{ U}$ $0  U$	_	5.3	_	- ns
	Turn-on time	t <sub>on</sub>		_	12	_	
	Fall time	t <sub>f</sub>			8.4	_	
	Turn-off time	t <sub>off</sub>		_	34	_	
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \simeq -24 \text{ V}, V_{GS} = -10 \text{ V},$	_	14		
Gate-source charge 1		Q <sub>gs1</sub>	$I_D = -3.4 \text{ A}$	_	1.4	_	nC
Gate-drain ("miller") charge		Q <sub>gd</sub>		_	2.7	_	

# Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I <sub>DRP</sub>	_	_	_	-13.6	Α
Forward voltage (diode)		V <sub>DSF</sub>	$I_{DR} = -3.4 \text{ A}, V_{GS} = 0 \text{ V}$	—	_	1.2	V

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N-ch

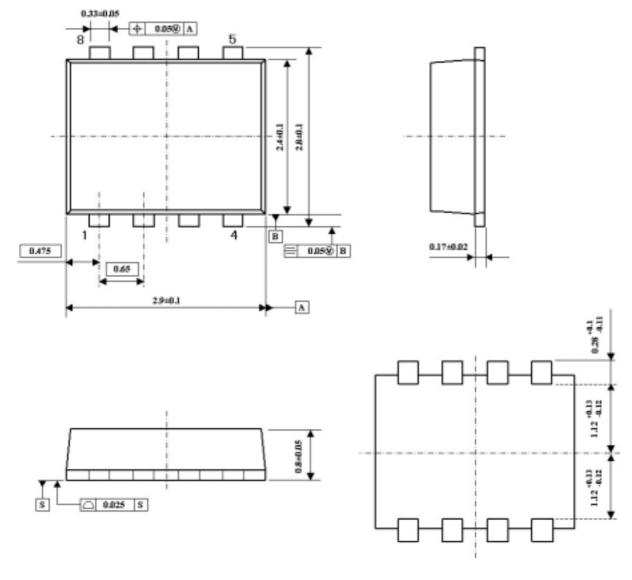
# **Electrical Characteristics (Ta = 25°C)**

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I <sub>GSS</sub>	V <sub>GS</sub> = ±16 V, V <sub>DS</sub> = 0 V	_	_	±10	μΑ
Drain cut-off curre	ent	I <sub>DSS</sub>	V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V	_	_	10	μΑ
Drain-source brea	akdown	V <sub>(BR) DSS</sub>	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	30		_	V
voltage		V (BR) DSX	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = -20 V	15	_	_	V
Gate threshold vo	oltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	1.3	_	2.5	V
Drain-source ON	registance	D	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 2.1 A	_	58	77	mΩ
Diain-source ON	resistance	R <sub>DS</sub> (ON)	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 2.1 A	_	38	50	
Forward transfer	admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 2.1 A	3.5	7.0	_	S
Input capacitance	;	C <sub>iss</sub>		_	470	_	
Reverse transfer capacitance		C <sub>rss</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	60	_	pF
Output capacitance		Coss		_	80	_	
	Rise time	t <sub>r</sub>	$V_{GS} \stackrel{10 \text{ V}}{\text{O} \text{ V}} \stackrel{I_D}{\text{I}} = 2.1 \text{ A}$ $V_{GS} \stackrel{0 \text{ V}}{\text{O} \text{ V}} \stackrel{V}{\text{O} \text{O} \text{ I}} \stackrel{O}{\text{V}} \stackrel{V}{\text{O} \text{O} \text{I}}$ $V_{DD} \approx 15 \text{ V}$ $V_{DD} \approx 15 \text{ V}$ $V_{DD} \approx 15 \text{ V}$	_	5.2	_	— ns
Cuitabina tima	Turn-on time	t <sub>on</sub>		_	8.3	_	
Switching time	Fall time	t <sub>f</sub>		_	4.0	_	
	Turn-off time	t <sub>off</sub>		_	22	_	
Total gate charge (gate-source plus gate-drain)		Qg	V <sub>DD</sub> ≈ 24 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 6 A	_	10	_	nC
Gate-source charge 1		Q <sub>gs1</sub>		_	1.7	_	
Gate-drain ("miller") charge		$Q_{gd}$			2.4	_	

# Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I <sub>DRP</sub>	_	_	_	16.8	Α
Forward voltage (diode)		V <sub>DSF</sub>	I <sub>DR</sub> = 4.2 A, V <sub>GS</sub> = 0 V	_	_	-1.2	V

注 7: 外形図



- 1 . Source 1
- 5 . Drain 2
- 2 . Gate 1
- 3 . Source2 4 . Gate2
- 6 . Drain2 7 . Drain1
- 8 . Drain1

#### RESTRICTIONS ON PRODUCT USE

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